



JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO., LTD

TO-252-2LK Plastic-Encapsulate Thyristors

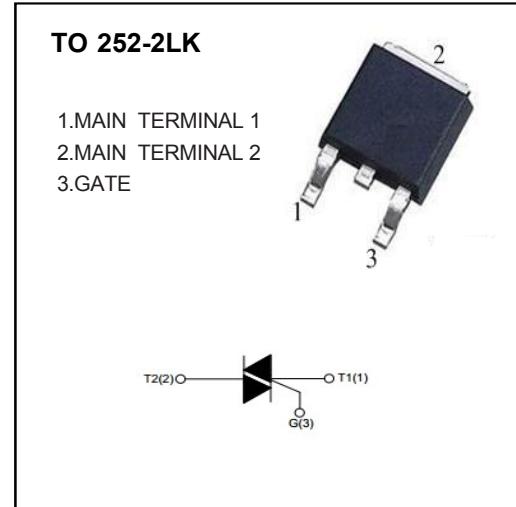
CT404D 4Q TRIACs

MAIN CHARACTERISTICS

$I_{T(RMS)}$		4A
V_{DRM}/V_{RRM}	CT404D-600S/C	600V
	CT404D-800S/C	800V
V_{TM}		1.55V

FEATURES

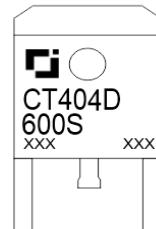
- NPNPN 5-layer Structure TRIACs
- Mesa Glass Passivated Technology
- Multi Layers Metal Electrodes
- High Junction Temperature
- Good Commutation Performance



APPLICATIONS

- Heater Control
- Motor Speed Controller
- Mixer

MARKING



CT404D:Series Code
600S:Depends on V_{DRM} and I_{GT}
XXX:Internal Code

ABSOLUTE RATINGS ($T_a=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test condition		Value		Unit	
V_{DRM}/ V_{RRM}	Repetitive peak off-state voltage	$T_j=25^\circ\text{C}$	CT404D-600S/C	600		V	
			CT404D-800S/C	800		V	
$I_{T(RMS)}$	RMS on-state current	TO-252-2LK($T_C \leq 110^\circ\text{C}$), Fig. 1,2		4		A	
I_{TSM}	Non repetitive surge peak on-state current	Full sine wave , $T_j(\text{init})=25^\circ\text{C}$, $tp=20\text{ms}$; Fig. 3,5		35		A	
I^2t	I^2t value	$tp=10\text{ms}$		6.1		A^2s	
dI_T/dt	Critical rate of rise of on-state current	$I_G=2*I_{GT}$, $tr \leq 10\text{ns}$, $F=120\text{Hz}$, $T_j=125^\circ\text{C}$	$I - II - III$	50	$\text{A}/\mu\text{s}$		
			IV	10			
I_{GM}	Peak gate current	$tp=20\mu\text{s}$, $T_j=125^\circ\text{C}$		2		A	
$P_{G(AV)}$	Average gate power	$T_j=125^\circ\text{C}$		0.5		W	
T_{STG}	Storage temperature			$-40 \sim +150$		$^\circ\text{C}$	
T_j	Operating junction temperature			$-40 \sim +125$			

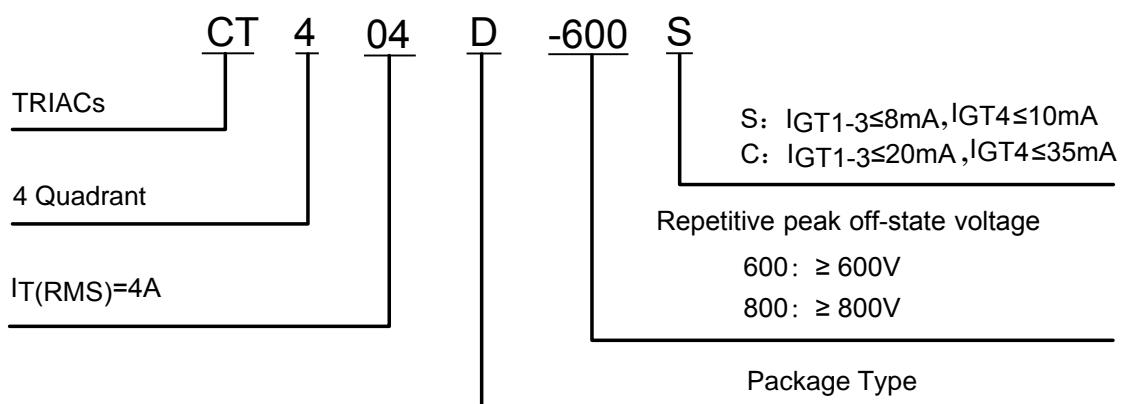
ELECTRICAL CHARACTERISTICS ($T_a=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test condition	Value		Unit
			S	C	
I_{GT}	Gate trigger current	$V_D=12\text{V}$, $I_T=0.1\text{A}$, $T_j=25^\circ\text{C}$, Fig. 6	≤ 8	≤ 20	mA
			≤ 10	≤ 35	
V_{GT}	Gate trigger voltage	I - II - III - IV	≤ 1.3		V
V_{GD}	Non-triggering gate voltage	$V_D=V_{DRM}$, $T_j=125^\circ\text{C}$	≥ 0.2		V
I_H	Holding current	$V_D=12\text{V}$, $I_{GT}=0.1\text{A}$, $T_j=25^\circ\text{C}$, Fig. 6	≤ 10	≤ 15	mA
I_L	Latching current		≤ 10	≤ 15	mA
			≤ 15	≤ 20	mA
dV_D/dt	Critical rate of rise of off-state	$V_D=67\%V_{DRM}$, Gate Open $T_j=125^\circ\text{C}$	≥ 10	≥ 20	V/ μs
V_{TM}	On-state Voltage	$I_{TM}=6\text{A}$, $t_p=380\mu\text{s}$, Fig. 4	≤ 1.55		V
I_{DRM} / I_{RRM}	Repetitive peak off-state current	$V_D=V_{DRM}/V_{RRM}$, $T_j=25^\circ\text{C}$	≤ 5	≤ 5	μA
		$V_D=V_{DRM}/V_{RRM}$, $T_j=125^\circ\text{C}$	≤ 0.5	≤ 0.5	mA

THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
$R_{th} (j-c)$	Junction to case (AC)	3.0	$^\circ\text{C/W}$
$R_{th} (j-a)$	Junction to ambient	70	$^\circ\text{C/W}$

PART NUMBER



CHARACTERISTICS CURVES

FIG.1: Maximum power dissipation versus RMS on-state current (full cycle)

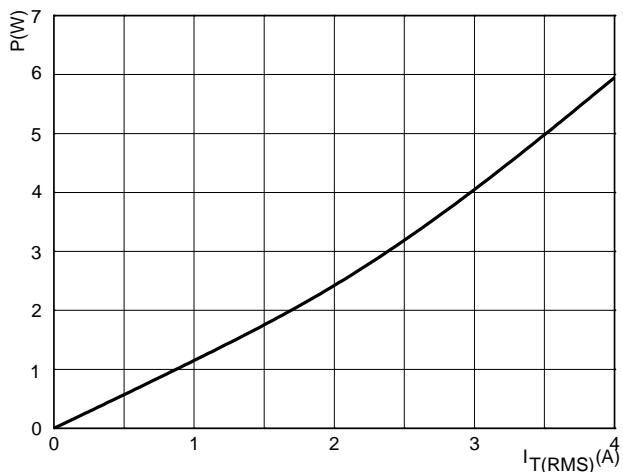


FIG.2: RMS on-state current versus case temperature (full cycle)

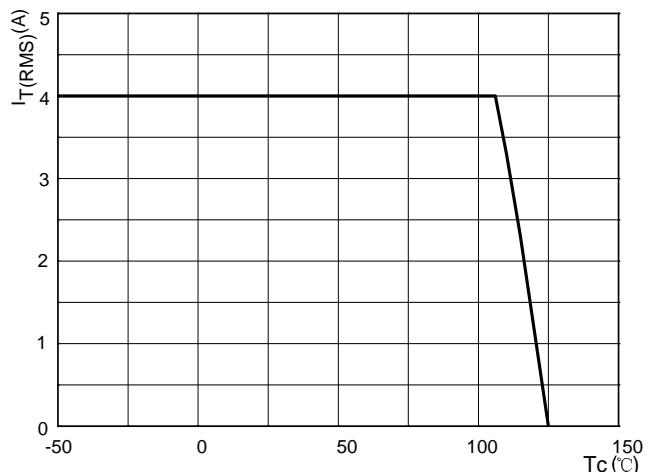


FIG.3: Surge peak on-state current versus number of cycles

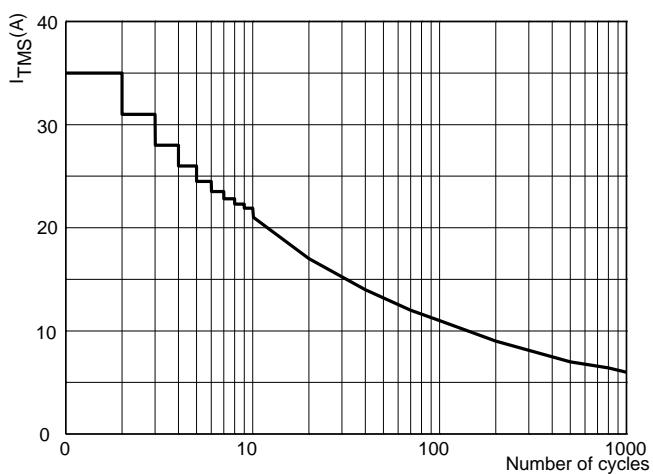


FIG.4: On-state characteristics (maximum values)

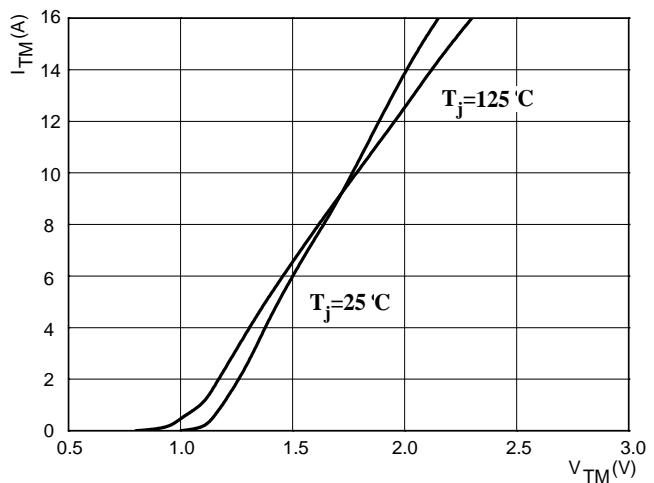


FIG.5: Non-repetitive surge peak on-state current for a sinusoidal pulse with width $t_p < 10\text{ms}$

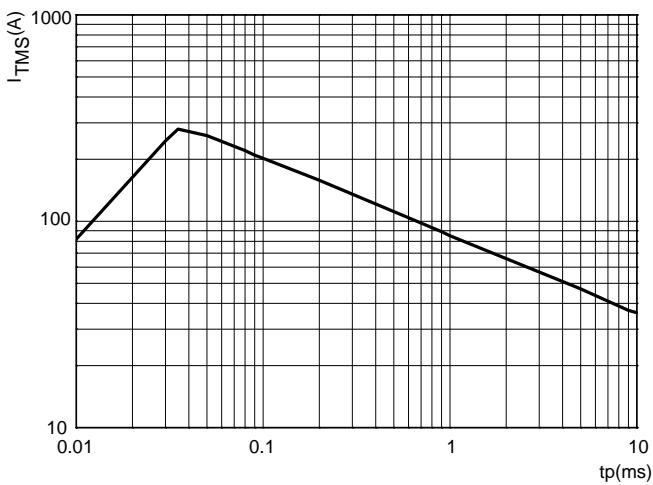
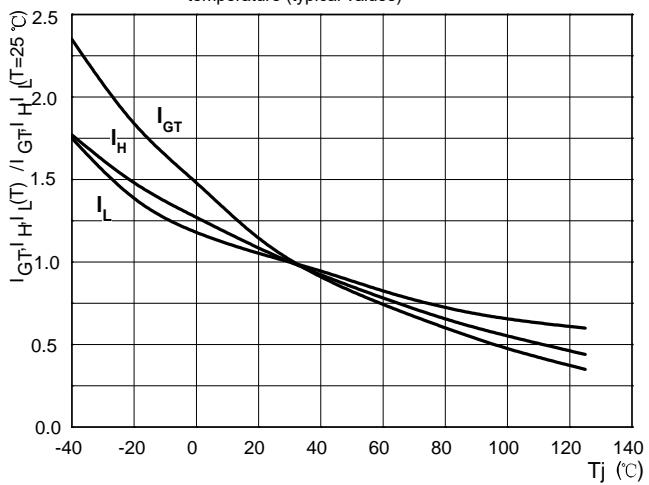
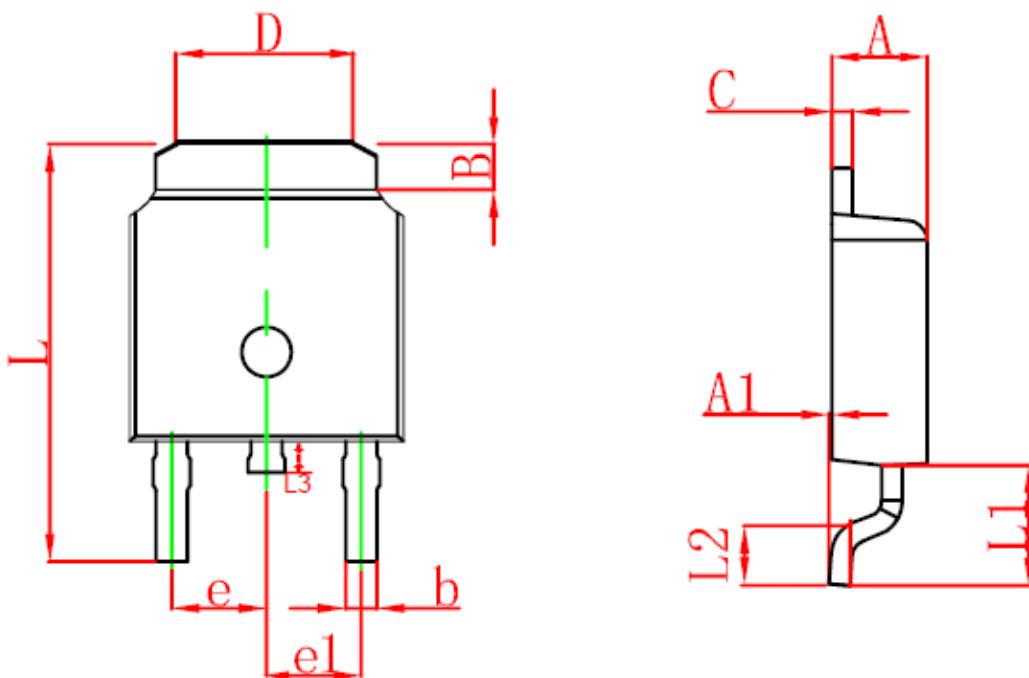


FIG.6: Relative variations of gate trigger current, holding current and latching current versus junction temperature (typical values)



TO-252-2LK PACKAGE OUTLINE DIMENSIONS



Symbol	Dimensions In Millimeters	
	Min.	Max.
A	2.100	2.500
A1	0.000	0.127
B	1.070	1.470
b	0.710	0.810
C	0.700	0.900
D	3.400	3.800
e	2.250	2.350
e1	2.250	2.350
L	10.000	10.400
L1	2.600	3.000
L2	1.400	1.700
L3	0.600	1.000